

Features

- N-channel, normal level
- Enhanced avalanche ruggedness
- Maximum 175°C junction temperature

Applications

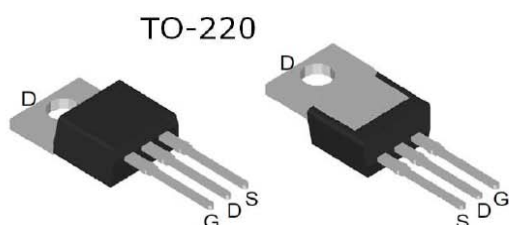
- DC/DC and AC/DC converters
- Brushed and BLDC Motor drive systems
- Battery powered systems

Product Summary

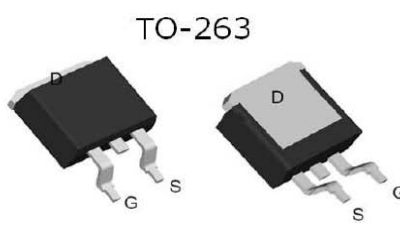
V _{DS}	200V
R _{DS(on)}	11.3mΩ
I _D	95A

100% DVDS Tested

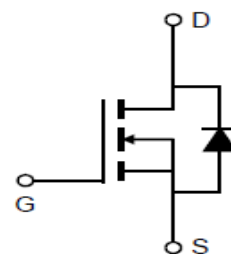
100% Avalanche Tested



SFP135N200C3



SFB132N200C3



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
SFP135N200C3	135N200C3	TO-220	Tube	N/A	N/A	50pcs
SFB132N200C3	132N200C3	TO-263	Tube	N/A	N/A	50pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	200	V
Continuous drain current	I _D	95	A
T _C = 25°C (Silicon limit)		120	
T _C = 25°C (Package limit)		67	
T _C = 100°C (Silicon limit)			
Pulsed drain current (T _C = 25°C, t _p limited by T _{jmax})	I _{D pulse}	380	A
Avalanche energy, single pulse (L=0.5mH, R _g =25Ω)	E _{AS}	1406	mJ
Gate-Source voltage	V _{GS}	±20	V
Power dissipation (T _C = 25°C)	P _{tot}	300	W
Operating junction and storage temperature	T _j , T _{stg}	-55...+175	°C

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R_{thJC}	0.5	°C/W
Thermal resistance, junction – ambient(min. footprint)	R_{thJA}	62.5	

Electrical Characteristic (at $T_j = 25\text{ }^{\circ}\text{C}$, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV_{DSS}	200	219	-	V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	3.0	3.7	4.5	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Zero gate voltage drain current	I_{DSS}	-	0.05	1	μA	$V_{DS}=200V, V_{GS}=0V$ $T_j=25^{\circ}\text{C}$ $T_j=125^{\circ}\text{C}$
Gate-source leakage current	I_{GSS}	-	10	100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	11.3	13.5	mΩ	$V_{GS}=10V, I_D=50A$ TO-220
		-	11.0	13.2		TO-263
Transconductance	g_{fs}	-	90	-	S	$V_{DS}=10V, I_D=50A$

Dynamic Characteristic

Input Capacitance	C_{iss}	-	6900	-	pF	$V_{GS}=0V, V_{DS}=100V,$ $f=1\text{MHz}$
Output Capacitance	C_{oss}	-	401	-		
Reverse Transfer Capacitance	C_{rss}	-	7	-		
Gate Total Charge	Q_G	-	83	-	nC	$V_{GS}=10V, V_{DS}=100V,$ $I_D=50A, f=1\text{MHz}$
Gate-Source charge	Q_{gs}	-	39	-		
Gate-Drain charge	Q_{gd}	-	12	-		
Turn-on delay time	$t_{d(on)}$	-	37	-	ns	$V_{GS}=10V, V_{DS}=100V,$ $R_G=3.0\Omega$
Rise time	t_r	-	12	-		
Turn-off delay time	$t_{d(off)}$	-	62	-		
Fall time	t_f	-	8	-		
Gate resistance	R_G	-	2.8	-	Ω	$V_{GS}=0V, V_{DS}=0V,$ $f=1\text{MHz}$

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Diode continuous forward current	I_S	-	-	95	A	-
Diode pulse current	$I_{S,pulse}$	-	-	380	A	pulsed; $t_p \leq 10 \mu s$
Body Diode Forward Voltage	V_{SD}	-	0.9	1.2	V	$V_{GS}=0V, I_{SD}=90A$
Body Diode Reverse Recovery Time	t_{rr}	-	167	-	ns	$I_F=50A,$ $dI/dt=100A/\mu s$
Body Diode Reverse Recovery Charge	Q_{rr}	-	1010	-	nC	$I_F=50A,$ $dI/dt=100A/\mu s$

Typical Performance Characteristics

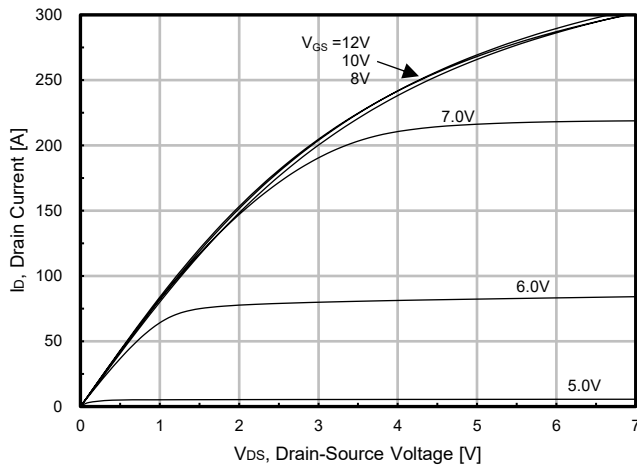


Fig. 1. Output Characteristics (25°C)

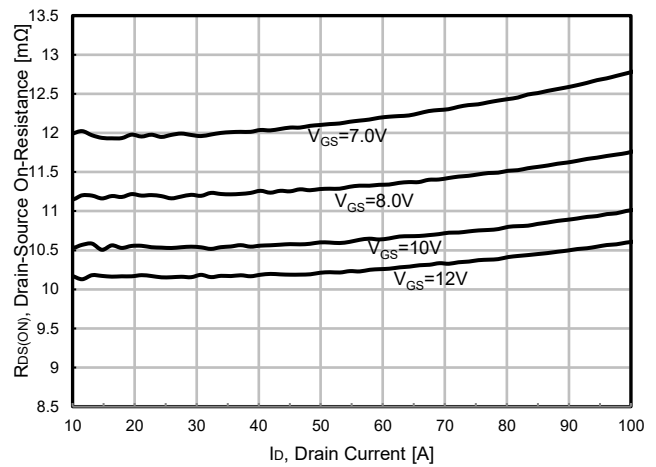


Fig. 2. Static On-Resistance Variation

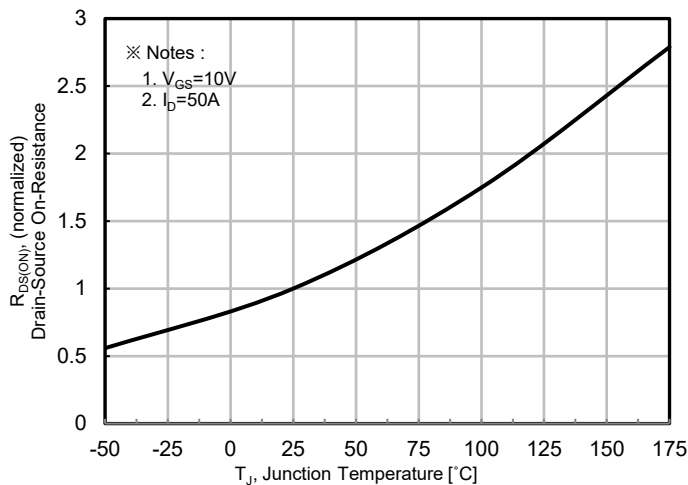


Fig. 3. On-Resistance vs. Junction Temperature

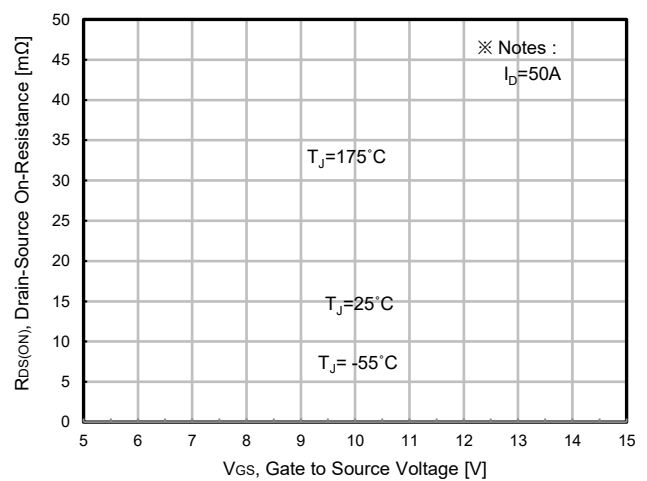


Fig. 4. On-Resistance vs. Gate to source Voltage

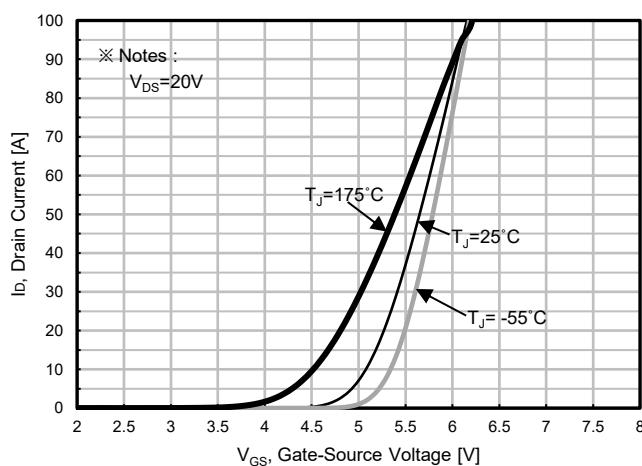


Fig. 5. Transfer Characteristics

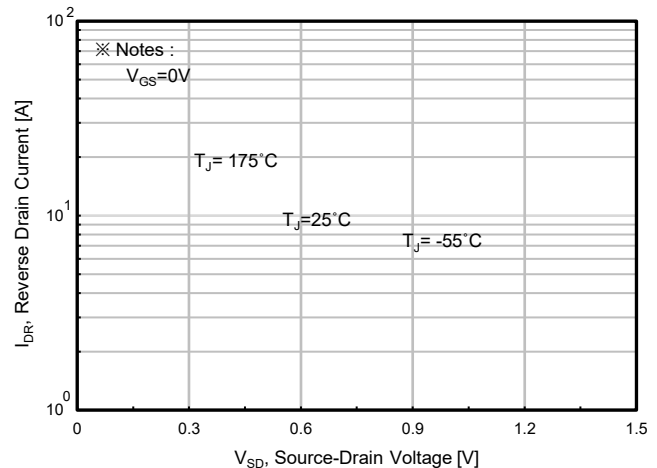


Fig. 6. Body Diode Forward Voltage Variation with Source Current and Temperature

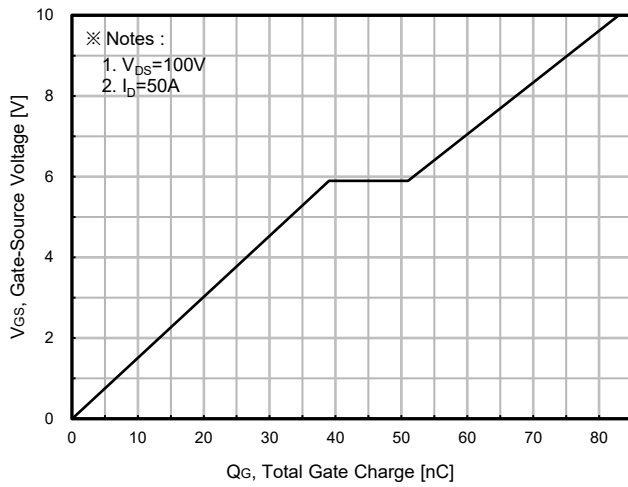


Fig. 7. Gate Charge

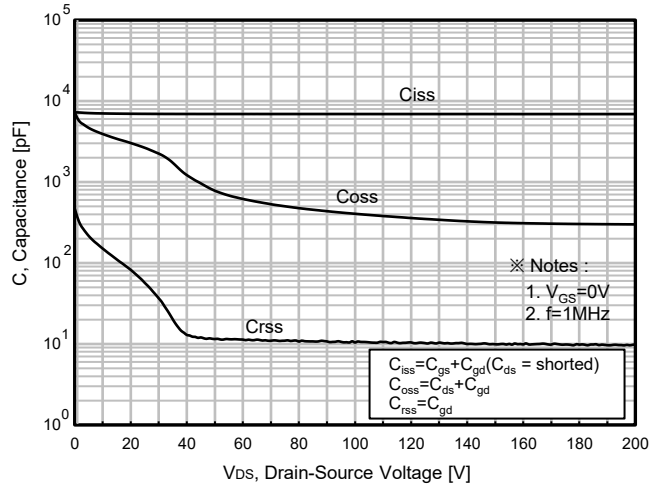


Fig. 8. Capacitance

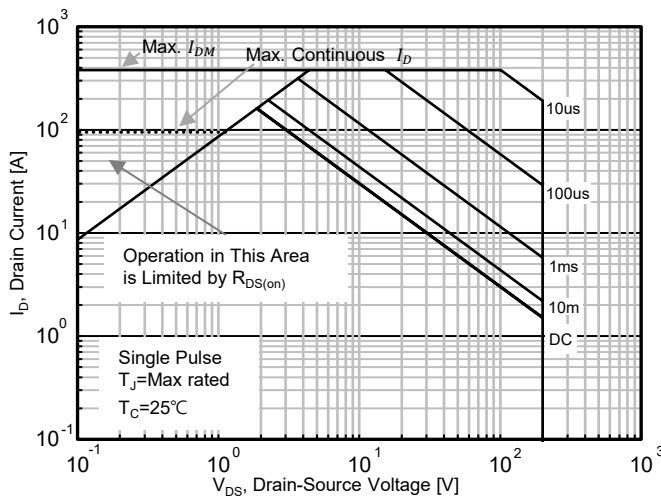


Fig. 9. Safe Operating Area, Junction-to-Ambient

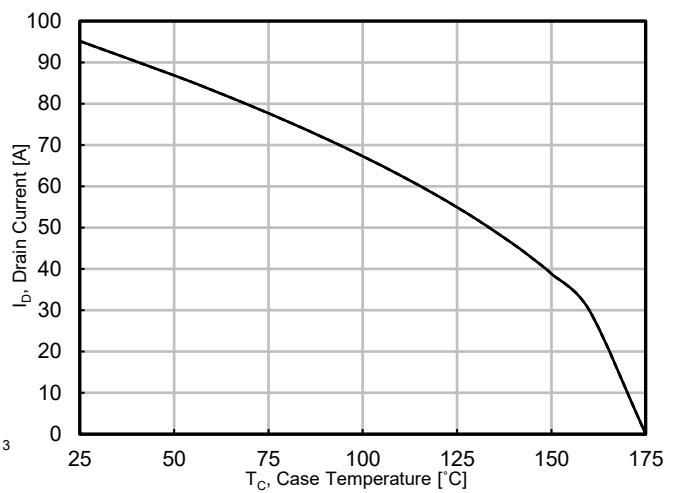


Fig. 10. Maximum Drain vs. Case Temperature

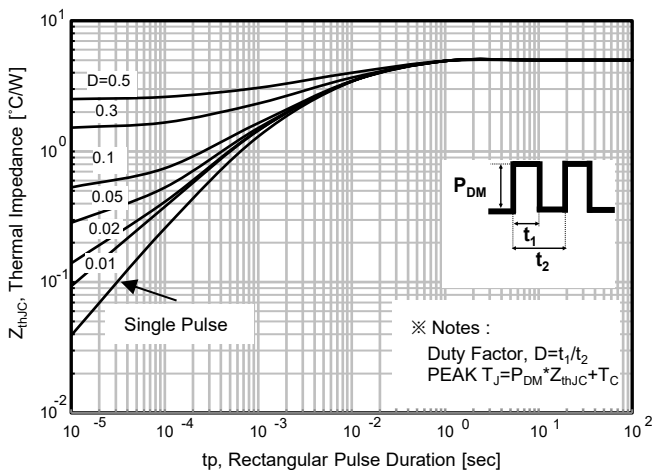


Fig. 11. Transient Thermal Impedance Junction to Case (R_{thjc})

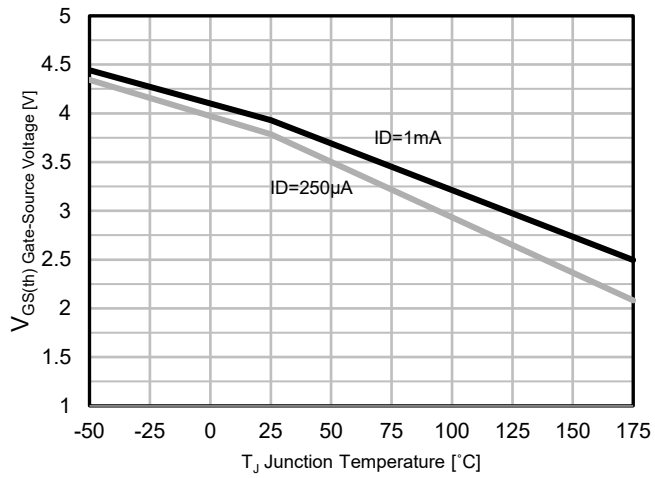


Fig.12 Gate-Source Threshold Voltage vs. Temperature

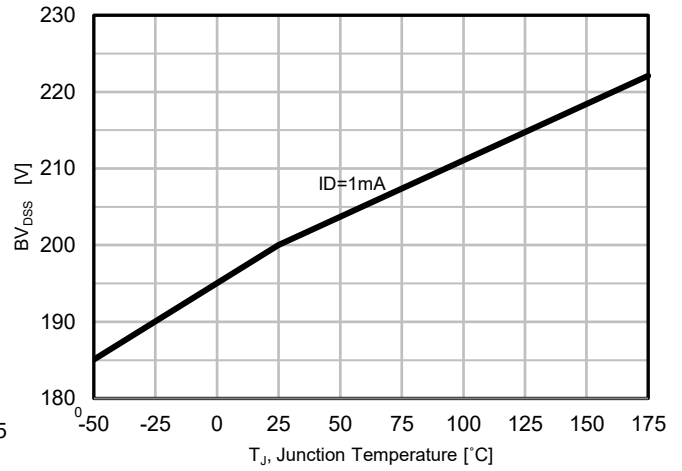
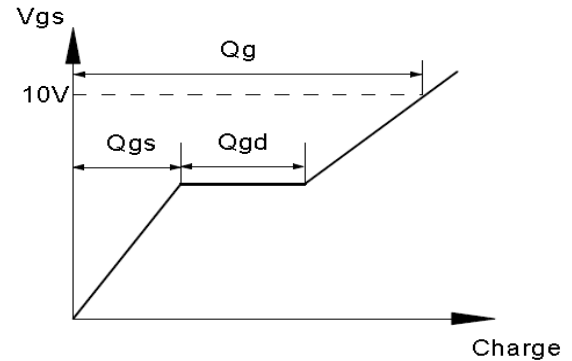
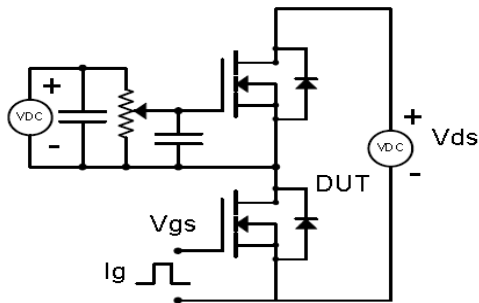


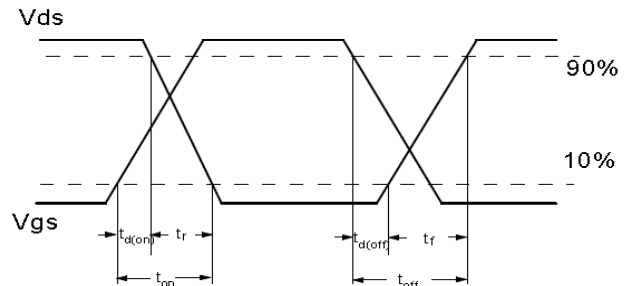
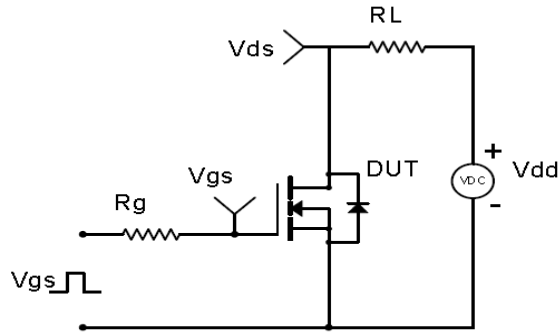
Fig.13 Drain-Source Voltage vs. Temperature

Test Circuit & Waveform

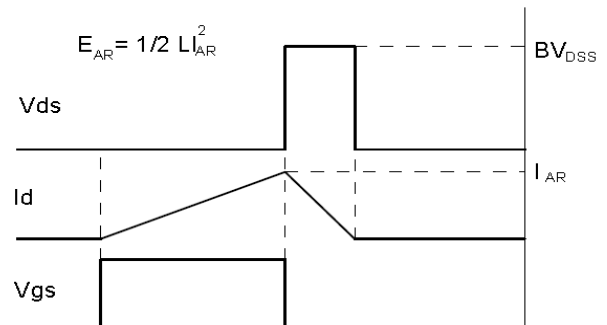
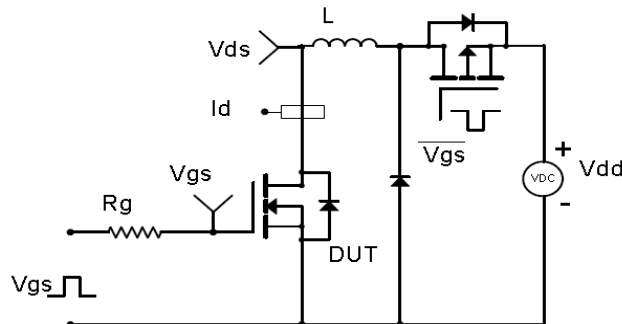
Gate Charge Test Circuit & Waveform



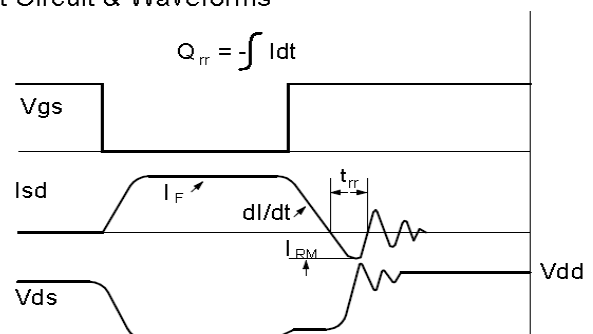
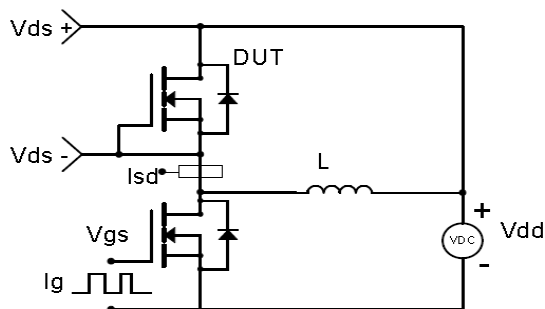
Resistive Switching Test Circuit & Waveforms



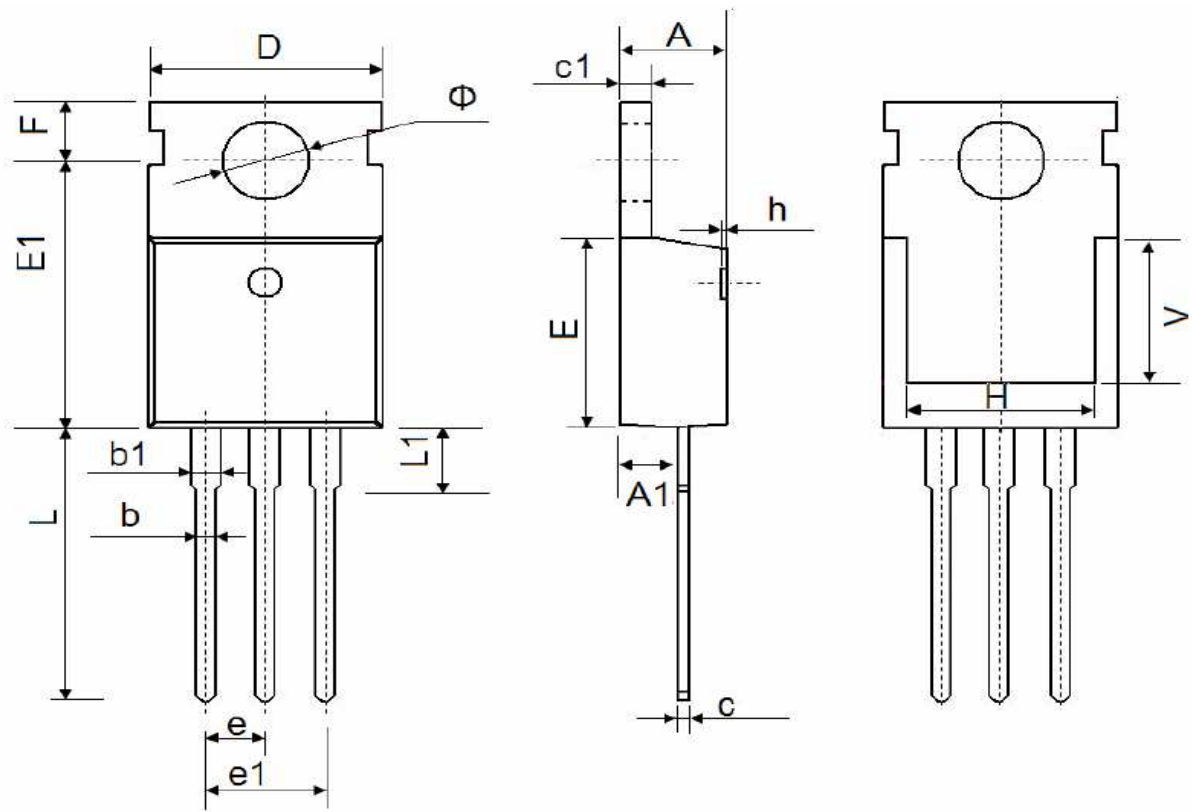
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

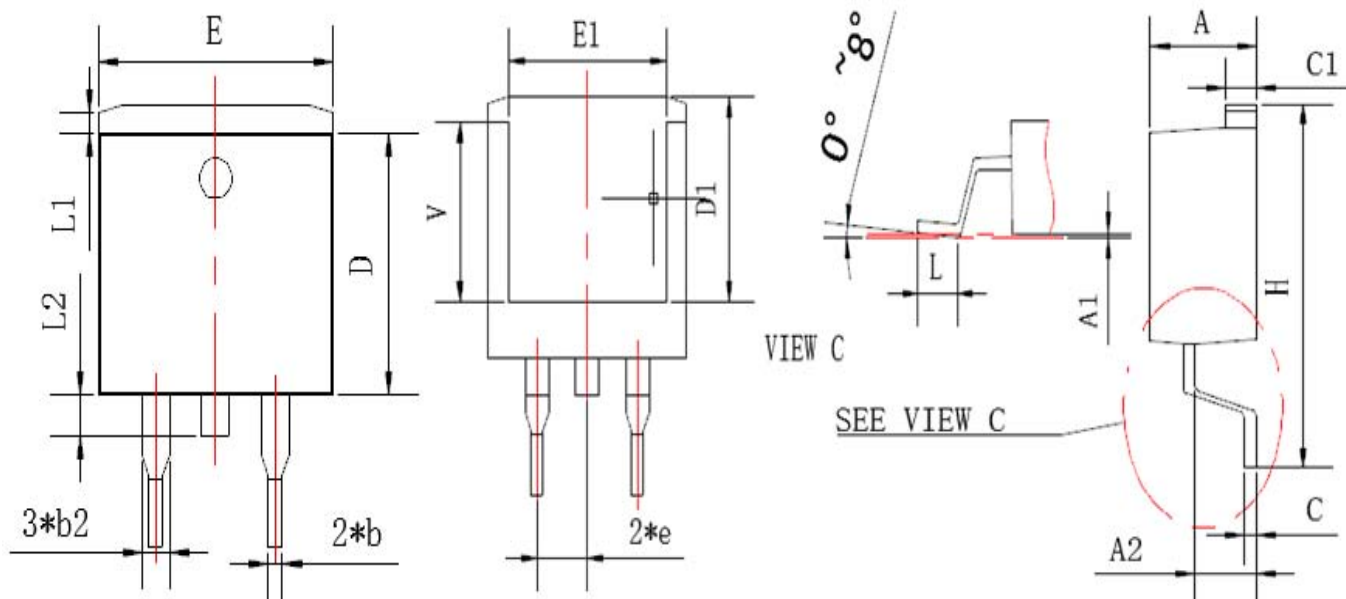


Package Outline: TO-220-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.30	4.80	0.169	0.189
A1	2.20	2.70	0.087	0.106
b	0.70	0.95	0.028	0.037
b1	1.10	1.50	0.043	0.059
c	0.40	0.65	0.016	0.026
c1	1.20	1.45	0.047	0.057
D	9.70	10.30	0.382	0.406
E	8.75	9.65	0.344	0.380
E1	12.50	13.10	0.492	0.516
e	2.540 Typ.		0.100 Typ.	
e1	4.98	5.18	0.196	0.204
F	2.60	3.00	0.102	0.118
H	7.00	8.40	0.276	0.331
h	0	0.3	0	0.012
L	12.75	13.90	0.502	0.547
L1	2.85	3.40	0.112	0.134
V	6.700Ref.		0.264Ref.	
Φ	3.50	3.80	0.138	0.150

Package Outline: TO-263



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.30	4.80	0.169	0.189
A1	0.00	0.25	0.000	0.010
A2	2.35	2.70	0.093	0.106
b	0.70	0.94	0.028	0.037
b2	1.15	1.35	0.045	0.053
C	0.35	0.65	0.014	0.026
C1	1.20	1.40	0.047	0.055
D	8.40	9.40	0.331	0.370
D1	7.80	8.10	0.307	0.319
e	2.540 Typ.		0.100 Typ.	
E	9.85	10.30	0.388	0.406
E1	7.00	8.50	0.276	0.335
H	15.00	15.70	0.591	0.618
L	2.30	2.80	0.091	0.110
L1	0.90	1.30	0.035	0.051
V	6.700Ref.		0.264Ref	
L2	1.00	1.50	0.039	0.059

Revision History

Revision	Date	Major changes
1.0	2022-07-15	Release of provisional version

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

Scilicon Electric reserves the right to improve product design,function and reliability without notice.